

[Signature]
LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT
Micron Technology, Inc.FILING DATE
Filed Herewith 2/24/00 GROUP
2858-2829

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	RR	Product Description for Ball Grid Probe BT500-C3 from the Web Page of Toku Denshi America, Inc., 1 page					
	AS						
	AT						

EXAMINER

[Signature]

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.
Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micro Technology, Inc.FILING DATE
Filed Herewith 2/24/00GROUP
Unknown 2829

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

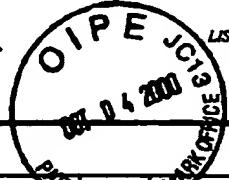
	AK	Product Description for Double Ended Probes, BT052 Series, from the Web Page of Rika-Denki America, Inc. 1 page
	AS	Product Description for Test Connectors, RM-500-Series Probes, from the Web Page of Rika-Denki America, Inc. 1 page
	AT	Product Description for Cost Effective Interconnections for High I/O Products from the Web Page of Rika-Denki America, Inc. 1 page

EXAMINER
*Mark Nguyen*DATE CONSIDERED
01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1363		SERIAL NO. 09/512,515 Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micro Technology, Inc.			
				FILING DATE Filed Herewith 2/24/00		GROUP 2825 Unknown 2058	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AB	09/032,184		Abram et al.			2/27/08
VN	AB	5,495,667	3/5/96	Farmworth et al.	29	843	—
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
							No
	AL						
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR	Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page					
	AS	Good Things Come in Small BGA/CSP Packages from the Web Page of Juhatech International Corporation, 1 page					
	AT	Product Description for Test Socket Contacts from the Web Page of Juhatech International Corporation, 1 page					
EXAMINER 2 <i>Paul Nguyen</i>		DATE CONSIDERED 01/26/2001					

**EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.*

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed HerewithGROUP
205 8029

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	4,560,216	12/24/85	Egawa			
VN	4,754,555	7/5/88	Stillman			
VV	5,475,317	12/12/95	Smith			
AD						
AE						
AP						
AG						
AH						
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
AL							
AM							
AN							
AO							
AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AR	Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page
AS	Good Things Come in Small BGA/CSP Packages from the Web Page of Johnstech International Corporation, 1 page
AT	Product Description for Test-Socket Connectors from the Web Page of Johnstech International Corporation, 1 page

EXAMINER

Mark Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
February 24, 2000GROUP
Unknown2858
1829

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VV	AA	5,375,052	6/28/94	Yamashita			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		
	AS		
	AT		

RECEIVED

MAY 03 2000

TECHNOLOGY CENTER 2800

EXAMINER

Mark Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered.
 Include copy of this form with next communication to applicant.

1 of 1

Form PTO-149 O I P E U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ART CITED BY APPLICANT (CITED DOCUMENTS & APPPLICANT)				ATTY. DOCKET NO. M72-130	SERIAL NO. 09/512,948	
				APPLICANT David Horowitz		
				FILING DATE February 24, 2000	GROUP 2805 7829	
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Applicable
VN	AA 5,612,576	3/18/97	Summaroff et al.			
VN	AB 5,719,333	2/17/98	Hoyer et al.			
VN	AC 5,631,233	11/5/99	Melofci et al.			
VN	AO 5,919,540	7/1/00	Barton et al.			
VN	AE 5,551,253	9/2/96	Makada et al.			
VN	AF 5,492,011	8/20/98	Amano et al.			
AG						
AM						
AJ						
FOREIGN PATENT DOCUMENTS						
	Document Number	Date	Country	Class	Subclass	Translation
AK						Yes No
AL						
AM						
AO						
OTHER REFERENCES (including Author, Title, Date, Page/Board Pages, Etc.)						
VN	AP	"NTC and PTc Thermistors": http://www.thermistor.com/ntc.htm ; 1/7/00; 2 pages.				
VN	AR	"D-SB33 Linearized 4-Wire RTD Input": http://www.datasheet.com/DSB33.htm ; 1/7/00; 2 pages.				
VN	AS	"RTD": http://www.micromec.com/rtd.htm ; 1/7/00; 3 pages.				
VN	AT	"Low Cost Thermal-Rubber (TM) uses thin RTD": http://www.micromec.com/17874.htm ; 1/7/00; 1 page.				
VN	AU	"Silicon Processing for the VLSI Era": Volume 1 - Process Technology, Second Edition, S. Wolf et al., 2000; pp. 22-23 and pp. 841-845. (month unavailable)				
EXAMINER <i>anh Nguyen</i>	DATE CONSIDERED			01/22/04		
EXAMINER: Indicate if reference considered, whether or not citation is in conformance with MPEP 600. Cross line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. ME22-1263	SERIAL NO. 03/512,968
 LIST OF ART CITED BY APPLICANT <small>(With forward dates if necessary)</small> <small>02-20-2003</small>				APPLICANT Necron Technology, Inc.	
				FILING DATE February 24, 2000	PRIORITY GROUP 2829
U.S. PATENT DOCUMENTS					
EXAMINER NAME	TYPE & TRADEMARK NUMBER	DATE	NAME	CROSS	SEARCHED
V/N	AA	3,710,251	1/21/973	Hegge et al.	
	AB				
	AC				
	AD				
OTHER REFERENCES (including Author, Title, Date, Page and Pages, Etc.)					
	AB				
	AF				
	AG				
	AH				
	AI				
	AJ				
	AK				
	AL				
EV317135597					
EXAMINER <i>mark Nguyen</i>	DATE CONSIDERED <i>01/22/04</i>				
<small>EXAMINER initials if reference considered, whether or not citation is in conformance with 35 U.S.C. § 102. Draw line through citation if not in conformance and not considered. Indicate copy of this form with next communication to applicant.</small>					

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					ATTY. DOCKET NO. M22-1363	SERIAL NO. 09512 569	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Motion Technology, Inc.		
					FILING DATE February 24, 2000	PRIORITY GROUP 2900 829	
U.S. PATENT DOCUMENTS							
Ref. No.	Document Number	Date	Name	Class	Examiner	Filed Date if Applicable	
1/1	AA 4,912,600	3/1/90	Jasper et al.	361	TDC		
1/1	AB 5,436,436	7/1/95	Mosher	257	MS		
1/1	AC 5,969,639	10/1/99	Laud et al.	340	B-17		
	AD						
OTHER REFERENCES (Including Author, Title, Date, Publication Pages, Etc.)							
A6							
A7							
A8							
A9							
A10							
A11							
A12							
A13							
A14							
EXAMINER: <i>mark Nguyen</i>	DATE CONSIDERED: 01/22/04						
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Drawing portion citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE <small>EST. 1790. CITED BY APPLICANT (Use where appropriate)</small> <small>O I P E</small> <small>01/20/2003</small>				ATTY. DOCKET NO. M27-1333	SERIAL NO. 05/12/08		
				APPLICANT Motor Technology, Inc.			
				FILED DATE February 24, 2000	PRIORITY GROUP 205A		
U.S. PATENT DOCUMENTS							
Examiner Initial	TRADEMARK Number	Date	Name	Class	Subclass	Filing Date ✓ Appropriate	
WV	4,355,463	10/26/1982	Burns				
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
EXAMINER <i>mark Ngay</i>		DATE CONSIDERED <i>01/22/04</i>					
<small>EXAMINER: Initial if reference considered, whether or not claim is in conformance with MPEP 609. Drawings through section 4 not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-1363SERIAL NO.
09/512,968LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
February 24, 2000PRIORITY GROUP
2000 2829

st 12
spree
10/2001

U.S. PATENT DOCUMENTS

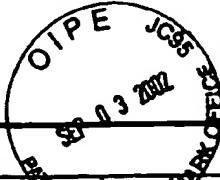
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						C 2000 10/24/00
	AC						C 2000 10/24/00
	AD						C 2000 10/24/00

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

VN	AE	S/N: 09/032,184; Filed 2/27/98; Akram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendments filed 3/3/00; Amendment filed 8/23/00;
		Original Application filed 2/27/98; Pending Claims.
VN	AF	Advertisement for Probe Technology: www.idinet.com ; Interconnect Devices, Inc., 1 page; 3/6/98
VN	AG	Good Things Come In Small BGA/CSP Packages: www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98
VN	AH	Product Description for Double Ended Probes, B1052 Series: www.tezprobe.com/products/b1052.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.
VN	AI	Product Description for Test Centers, RM-500 Series Probes, www.tezprobe.com/products/rm500.html ; Rika Denshi America, Inc.; 1 page; 2/4/98.
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products: www.tezprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.;
		I page; 2/4/98.
VN	AK	Product Description for Ball-Grid Probe B1303-C3; www.tezprobe.com/products/io.htm#b1303 ; Rika Denshi America, Inc.; 1 page; 2/4/98.
VN	Al	Product Description for Test Socket Connectors; www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98
EXAMINER	<i>Muth Nguyen</i>	DATE CONSIDERED <u>10/25/2001</u>

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTY. DOCKET NO. M122-1383	SERIAL NO. 09/512,968		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT David R. Hemberee			
				FILING DATE February 24, 2000	GROUP 2332 2829		
U.S. PATENT DOCUMENTS							
Examiner Initials	TRADEMARK OFFICE	Document Number	Date	Name	Class	Subclas s	Filing Date If Appropriate
VN		AA 3,440,407	4/22/69	Gobatos et al.			
		AB 3,614,345	10/18/71	Quinn			
		AC 3,653,306	8/8/72	Buithius et al.			
		AD 4,332,081	6/1/82	Francis			
		AE 4,518,944	5/21/85	Faris			
		AF 4,703,556	11/3/87	Hubner			
		AG 5,141,334	8/25/92	Castles			
		AH 5,347,869	9/20/94	Shie et al.			
		AI 5,406,109	4/11/95	Whitney			
		AJ 5,436,645	7/25/95	McArthur et al.			
		AK 5,446,437	8/29/95	Banden et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclas s	Translation
VN	AL	2338778	7/1977	France			Yes
VN	AM	58-12521	2/1981	Kobayashi, Japan			No
VN	AN	2-266482	11/1990	Yamanishi, Japan			
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
VN	AR	'Application Guide Temperature Sensors', Wadlow Electrical Manufacturing Company Catalog, pp. 775-778, 1992/1993.					
VN	AS	'In-Situ survey System of Resistive and Thermoelectric Properties of Either Pure or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum', Lechevalier, Lehterou, Richon, Sarrazin, & Gousset, J. Phys. II France, Vol. 5, pp. 409-418, 04/95 (Abstract only).					
VN	AT	'Temperature Metrology for CD Control in DUV Lithography', Jeffrey Parker and Wayne Renken, pp. 111-112, 114, 116, 09/17/97.					
EXAMINER <i>VN Nguyn</i>		DATE CONSIDERED 03/24/05					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
February 24, 2000PRIORITY GROUP
2658 2829

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA 6,004,471	12/21/1999	Chuang			
VN	AB 5,550,526	8/27/1996	Mottahed			
	AC					
	AD					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

VN	AE	P. Van Zant; "Microchip Fabrication;" (4th ed. 2000); pps 567-569.
	AF	
	AG	
	AH	
	AJ	
ZV182664188-		
	AJ	
	AK	
	AL	

EXAMINER

DATE CONSIDERED

12/09/02

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

 LIST OF ART CITED BY APPLICANT (Use second sheet if necessary)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. N22-1853	SERIAL NO. 09512,955	
		APPLICANT Micron Technology, Inc.		FILING DATE February 24, 2000	PRIORITY GROUP 285B 2829	
U.S. PATENT DOCUMENTS						
Examiner Initials	Document Number	Date	Name	Class	Subclass	Filing Date if Applicable
VN	AA 5,503,034	4/2/1996	Acaro et al.			
VN	AB 5,954,305	2/1/2000	Glovatsky et al.			RECEIVED
VR	AC 5,645,784	7/1/1997	Angelopoulos et al.			JUN 20 2004
VM	AD 5,437,159	8/1/1995	Brown et al.			
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
AE						
AF						
AG						
AH						
AI						
AJ						
AK						
AL						
EXAMINER <i>Mark Nguyen</i>		DATE CONSIDERED <i>09/03/04</i>				
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>						

JAN 28 2002

LIST OF ART CITED BY APPLICANT
(Use separate sheets if necessary)APPLICANT
David HembreeFILING DATE
February 24, 2000GROUP
2859- 2829

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclas s	Filing Date If Appropriate
VN	AA	5,612,574	3/18/97	Summerfelt et al.			
	AB	5,719,333	2/17/98	Hosoi et al.			
	AC	5,831,333	11/3/98	Malladi et al.			
	AD	5,910,548	7/6/99	Barron et al.			
	AE	5,551,283	9/3/96	Manaka et al.			
	AF	5,492,011	2/20/98	Amano et al.			
	AG						
	AH						
	AJ						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclas s	Translation	
							Yes	No
	AK							
	AL							
	AM							
	AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

VN	AP /	"NTC and PTC Thermistors"; http://www.thermodisc.com/ntcptc.html ; 1/7/98; 2 pages.
VN	AR /	"DI-5B35 Linearized 4-Wire RTD Input"; http://www.dataq.com/di5b35.html ; 1/7/98; 2 pages.
VN	AS /	"RTD"; http://www.mbsensors.com/rtds.html ; 1/7/98; 3 pages.
VN	AT /	"Low Cost Thermal-Ribbon (TM) uses thin film RTD"; http://www.minco.com/s17824nr.html ; 1/7/98; 1 page.
VN	AU /	"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology; Second Edition; S. Wolff et al.; 2000; pps 22-25 and pps. 841-845. <i>(month unavailable)</i>

EXAMINER

nh Nguyn

DATE CONSIDERED

05/30/2002

"EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant."

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- BLACK BORDERS**
- IMAGE CUT OFF AT TOP, BOTTOM OR SIDES**
- FADED TEXT OR DRAWING**
- BLURRED OR ILLEGIBLE TEXT OR DRAWING**
- SKEWED/SLANTED IMAGES**
- COLOR OR BLACK AND WHITE PHOTOGRAPHS**
- GRAY SCALE DOCUMENTS**
- LINES OR MARKS ON ORIGINAL DOCUMENT**
- REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY**
- OTHER: _____**

IMAGES ARE BEST AVAILABLE COPY.
As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.